FAIRCHILD SEMICONDUCTOR™

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MM74HCT00
Quad 2 Input NAND Gate

General Description

The MM74HCT00 is a NAND gates fabricated using advanced silicon-gate CMOS technology which provides the inherent benefits of CMOS—low quiescent power and wide power supply range. This device is input and output characteristic and pin-out compatible with standard 74LS logic families. All inputs are protected from static discharge damage by internal diodes to V_{CC} and ground.

MM74HCT devices are intended to interface between TTL and NMOS components and standard CMOS devices. These parts are also plug-in replacements for LS-TTL devices and can be used to reduce power consumption in existing designs.

Features

- TTL, LS pin-out and threshold compatible
- Fast switching: t_{PLH}, t_{PHL}=14 ns (typ)
- Low power: 10 μW at DC
- High fan out, 10 LS-TTL loads

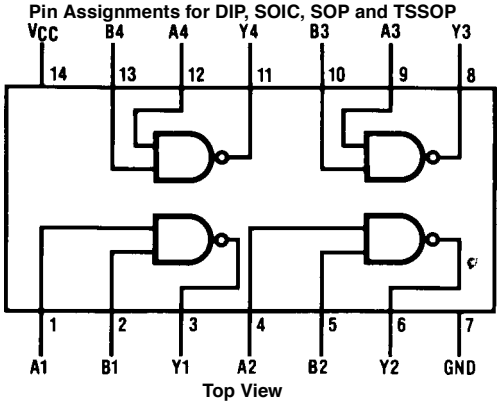
Ordering Code:

Order Number	Package Number	Package Description
MM74HCT00M	M14A	14-Lead Small Outline Integrate Circuit (SOIC), JEDEC MS-120, 0.150" Narrow
MM74HCT00SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
MM74HCT00MTC	MTC14	14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
MM74HCT00N	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram

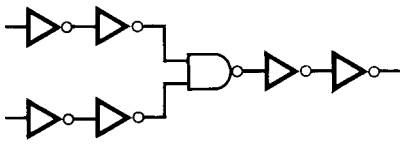
Pin Assignments for DIP, SOIC, SOP and TSSOP



Top View

Logic Diagram

(1 of 4 gates)



Absolute Maximum Ratings(Note 1)

(Note 2)

Supply Voltage (V_{CC})	−0.5 to +7.0V
DC Input Voltage (V_{IN})	−1.5 to V_{CC}+1.5V
DC Output Voltage (V_{OUT})	−0.5 to V_{CC}+0.5V
Clamp Diode Current (I_{IK}, I_{OK})	±20 mA
DC Output Current, per pin (I_{OUT})	±25 mA
DC V_{CC} or GND Current, per pin (I_{CC})	±50 mA
Storage Temperature Range (T_{STG})	−65°C to +150°C
Power Dissipation (P_D)	
(Note 3)	600 mW
S.O. Package only	500 mW
Lead Temperature (T_L)	
(Soldering 10 seconds)	260°C

Recommended Operating Conditions

	Min	Max	Units
Supply Voltage (V_{CC})	4.5	5.5	V
DC Input or Output Voltage (V_{IN}, V_{OUT})	0	V_{CC}	V
Operating Temperature Range (T_A)	−40	+85	°C
Input Rise or Fall Times (t_r, t_f)		500	ns

Note 1: Absolute Maximum Ratings are those values beyond which damage to the device may occur.

Note 2: Unless otherwise specified all voltages are referenced to ground.

Note 3: Power Dissipation temperature derating — plastic "N" package: −12 mW/°C from 65°C to 85°C.

DC Electrical Characteristics

V_{CC} = 5V ± 10% (unless otherwise specified)

Symbol	Parameter	Conditions	T_A = 25°C	T_A = −40 to 85°C	T_A = -55 to 125°C	Units
			Typ	Guaranteed Limits		
V_{IH}	Minimum HIGH Level Input Voltage			2.0	2.0	2.0	V
V_{IL}	Maximum LOW Level Input Voltage			0.8	0.8	0.8	V
V_{OH}	Minimum HIGH Level Output Voltage	V_{IN} = V_{IH} or V_{IL}					
		$\|I_{OUT}\|$ = 20 μA	V_{CC}	V_{CC}−0.1	V_{CC}−0.1	V_{CC}−0.1	V
		$\|I_{OUT}\|$ = 4.0 mA, V_{CC} = 4.5V	4.2	3.98	3.84	3.7	V
		$\|I_{OUT}\|$ = 4.8 mA, V_{CC} = 5.5V	5.2	4.98	4.84	4.7	V
V_{OL}	Maximum LOW Level Voltage	V_{IN} = V_{IH}					
		$\|I_{OUT}\|$ = 20 μA	0	0.1	0.1	0.1	V
		$\|I_{OUT}\|$ = 4.0 mA, V_{CC} = 4.5V	0.2	0.26	0.33	0.4	V
		$\|I_{OUT}\|$ = 4.8 mA, V_{CC} = 5.5V	0.2	0.26	0.33	0.4	V
I_{IN}	Maximum Input Current	V_{IN} = V_{CC} or GND, V_{IH} or V_{IL}		±0.05	±0.5	±1.0	μA
I_{CC}	Maximum Quiescent Supply Current	V_{IN} = V_{CC} or GND, I_{OUT} = 0 μA		1.0	10	40	μA
		V_{IN} = 2.4V or 0.5V (Note 4)	0.18	0.3	0.4	0.5	mA

Note 4: This is measured per input with all other inputs held at V_{CC} or ground.

AC Electrical Characteristics

V_{CC} = 5.0V, $t_r = t_f$ = 6 ns, C_L = 15 pF, T_A = 25°C (unless otherwise noted)

Symbol	Parameter	Conditions	Typ	Guaranteed Limit	Units
t_{PLH}, t_{PHL}	Maximum Propagation Delay		14	18	ns

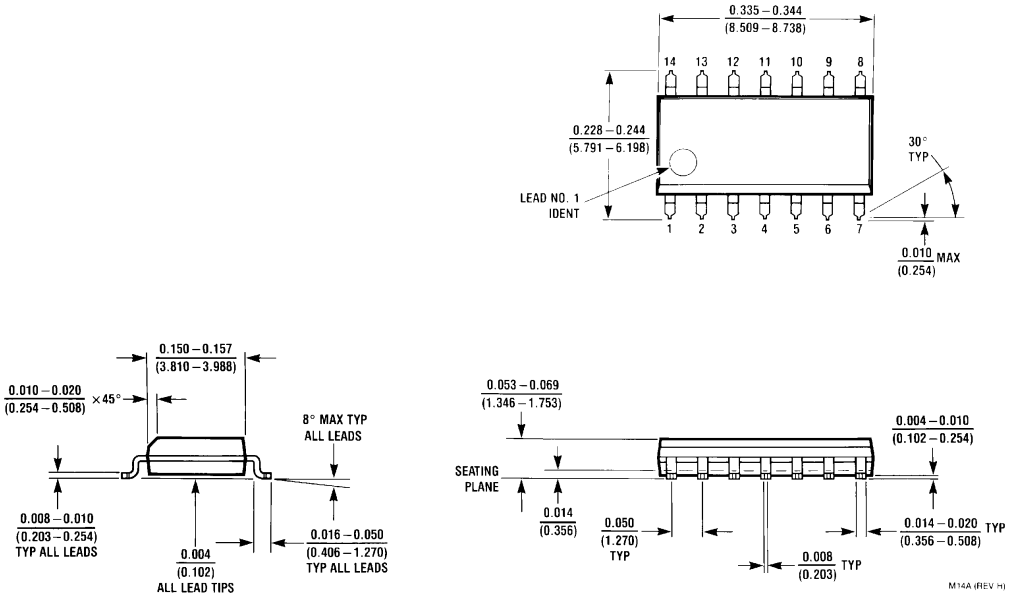
AC Electrical Characteristics

V_{CC} = 5.0V ±10%, $t_r = t_f$ = 6 ns, C_L = 50 pF (unless otherwise noted)

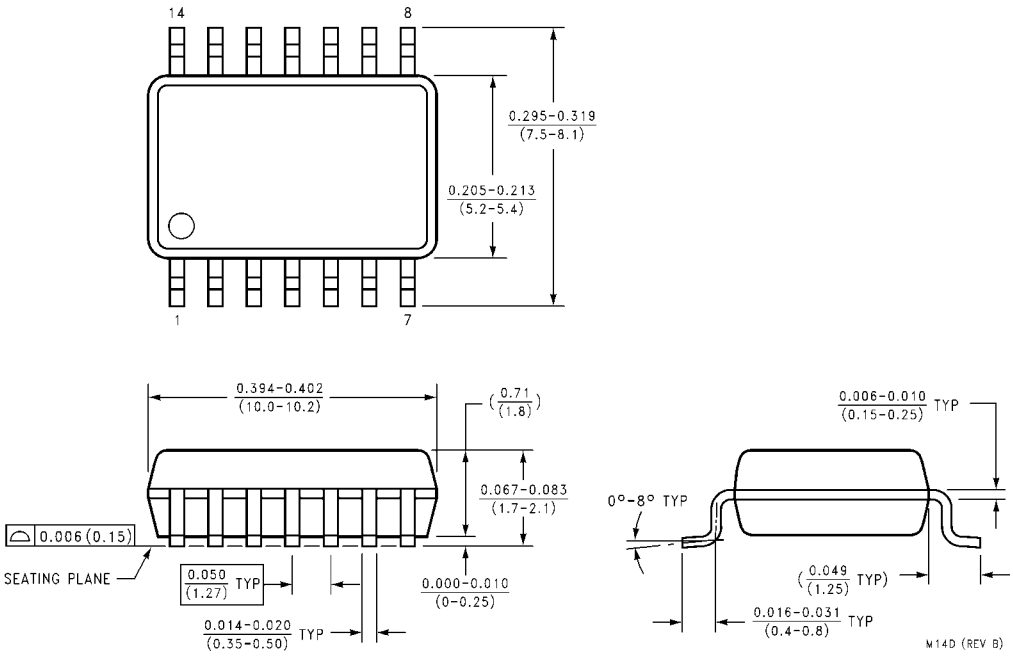
Symbol	Parameter	Conditions	T_A = 25°C	T_A = −40 to 85°C	T_A = −55 to 125°C		Units
			Typ	Guaranteed Limits			
t_{PLH}, t_{PHL}	Maximum Propagation Delay		18	23	29	35	ns
t_{THL}, t_{TLH}	Maximum Output Rise & Fall Time		8	15	19	22	ns
C_{PD}	Power Dissipation Capacitance	(Note 5)	30				pF
C_{IN}	Input Capacitance		5	10	10	10	pF

Note 5: C_{PD} determines the no load dynamic power consumption, $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$, and the no load dynamic current consumption, $I_S = C_{PD} V_{CC} f + I_{CC}$.

Physical Dimensions inches (millimeters) unless otherwise noted



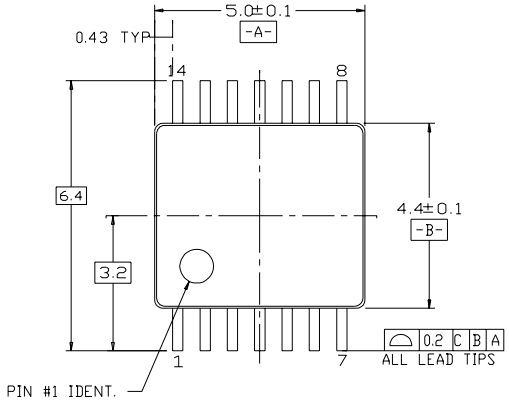
14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150" Narrow
Package Number M14A

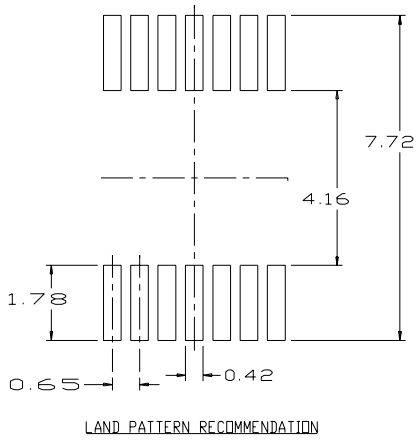


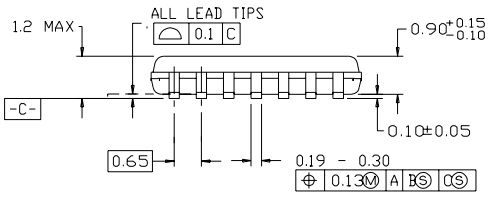
14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
Package Number M14D

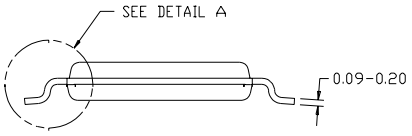
Physical Dimensions inches (millimeters) unless otherwise noted (Continued)

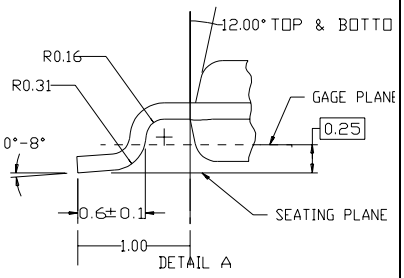
14LD, TSSOP, JEDEC MO-153, 4.4MM WIDE











NOTES:

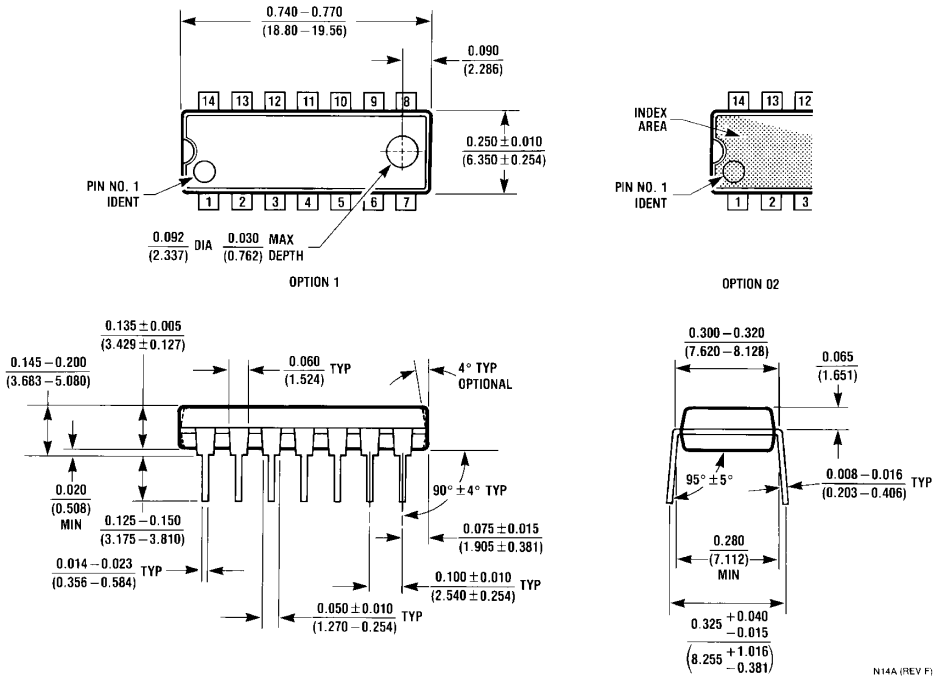
A. CONFORMS TO JEDEC REGISTRATION MO-153, VARIATION AB, REF NOTE 6, DATED 7/93

B. DIMENSIONS ARE IN MILLIMETERS

C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS

14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
Package Number MTC14

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



14-Line Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300" Wide
Package Number N14A

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